



Strip Test Socket

## Applications

- For simultaneous parallel testing before dicing

## Features

- It is possible to test desirable number of device sites.
- It is possible to design the sockets based on any types of autohandlers.
- It is suitable for Wafer Level CSP test.

## Probe

- Incorporating low profile contact probes designed for the test sockets.
- Enable to select probes by user's applications.